

Search Notes**Application/Control No.**

10/552,694

Examiner

SYED ZAIDI

Applicant(s)/Patent under Reexamination

FRICKE ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	452.2	4/11/2008	SZ
455	453	4/11/2008	SZ
455	512	4/11/2008	SZ
455	412.1	4/11/2008	SZ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	4/11/2008	SZ
Inventor : FRICKE ET AL.	4/11/2008	SZ
IEEE Xplore Database(http://ieeexplore.ieee.org/Xplore/DynWel.jsp)	4/11/2008	SZ
(455/452.2 455/453 455/512).CCLS.	4/11/2008	SZ
Consulted with SPE Nick Corsaro	4/11/2008	SZ